

Microscopy AND Microanalysis

EXPO Issue

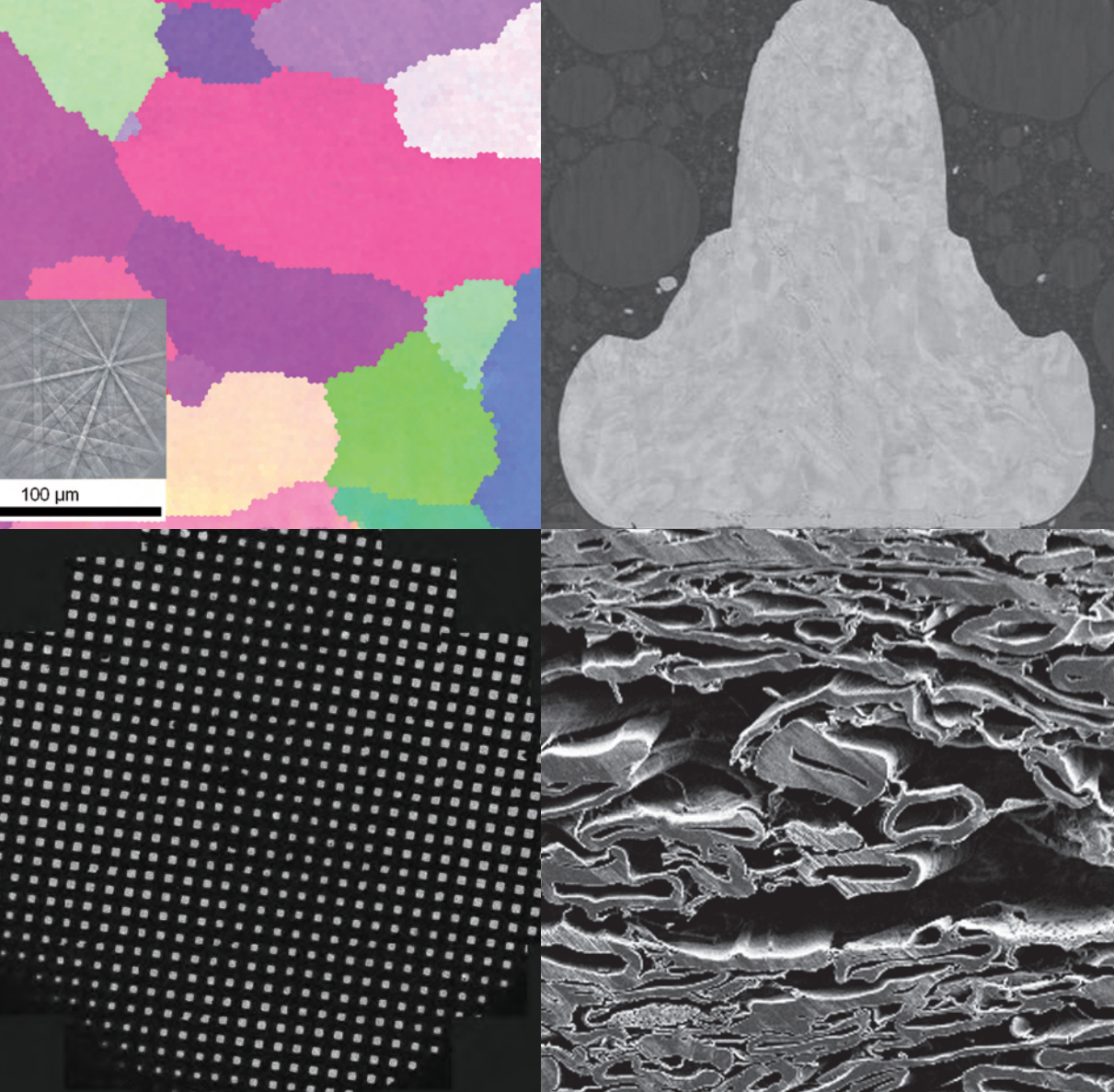
Microscopy & Microanalysis 2010

**68th Annual Meeting of the Microscopy Society of America
44th Annual Meeting of the Microbeam Analysis Society
43rd Annual Meeting of the International Metallographic Society
37th Annual Meeting of the Microscopical Society of Canada/
Société de Microscopie du Canada**

**Portland, Oregon, USA
August 1–5, 2010**



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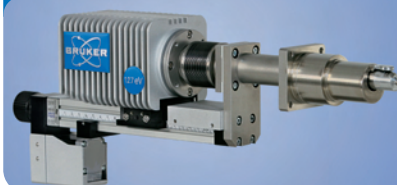
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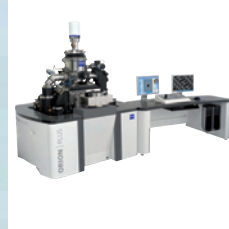
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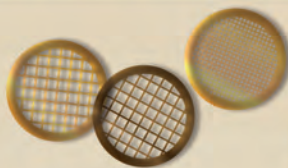
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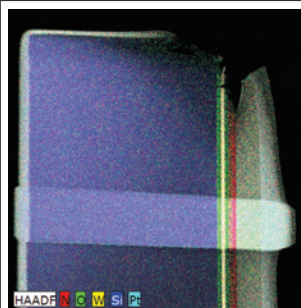
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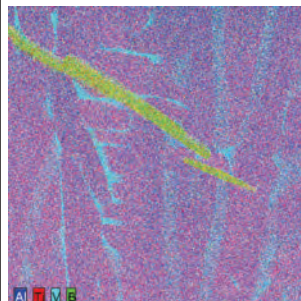
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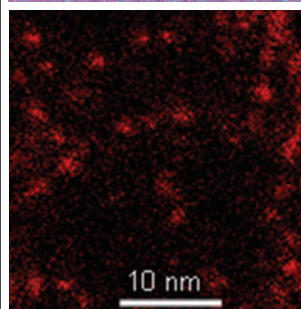
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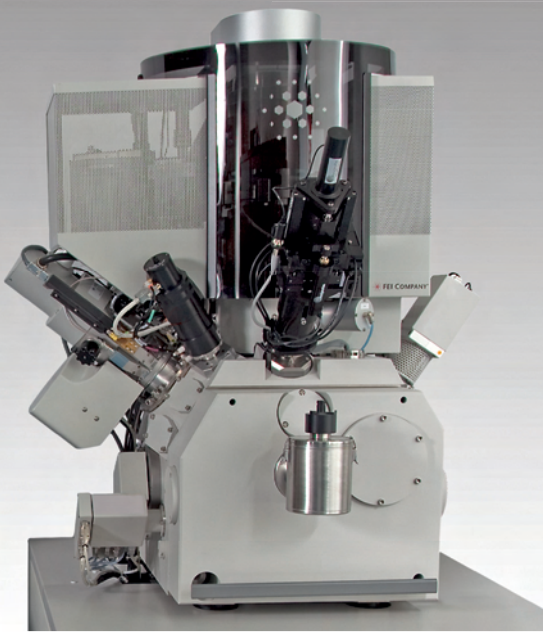


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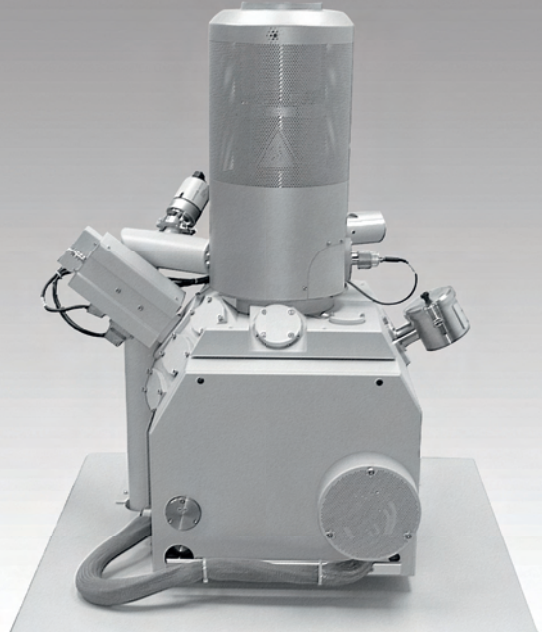
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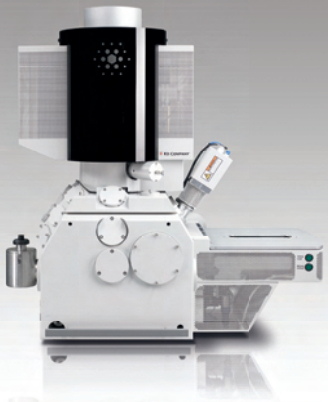
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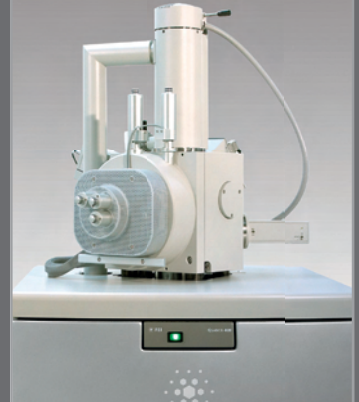
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